

Notice of References Cited	Application/Control No. 10/541,093		Applicant(s)/Patent Under Reexamination FUJINE ET AL.	
	Examiner ROBERT R. RAINEY		Art Unit 2629	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,095,393	08-2006	Lee, Baek-Woon	345/89
*	B	US-6,753,831	06-2004	Ide et al.	345/60
*	C	US-2004/0263495	12-2004	Sugino et al.	345/204
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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